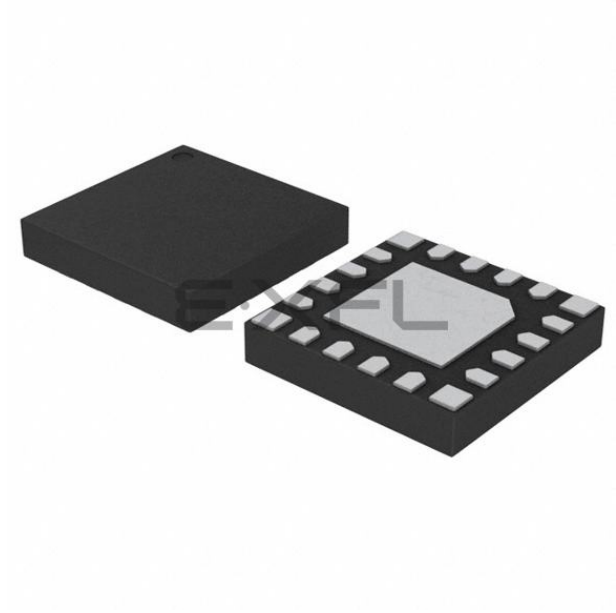

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	25MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	16
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512 x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 15x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	20-WFQFN Exposed Pad
Supplier Device Package	20-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb10f8a-a-qfn20

1. Feature List

The EFM8BB1 highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 25 MHz maximum operating frequency
- Memory:
  - Up to 8 kB flash memory, in-system re-programmable from firmware.
  - Up to 512 bytes RAM (including 256 bytes standard 8051 RAM and 256 bytes on-chip XRAM)
- Power:
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 18 total multifunction I/O pins:
  - All pins 5 V tolerant under bias
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 24.5 MHz oscillator with ±2% accuracy
  - Internal 80 kHz low-frequency oscillator
  - External CMOS clock option
- Timers/Counters and PWM:
  - 3-channel programmable counter array (PCA) supporting PWM, capture/compare, and frequency output modes
  - 4 x 16-bit general-purpose timers
  - Independent watchdog timer, clocked from the low frequency oscillator
- Communications and Digital Peripherals:
  - UART
  - SPI™ Master / Slave
  - SMBus™/I2C™ Master / Slave
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
- Analog:
  - 12-Bit Analog-to-Digital Converter (ADC)
  - 2 x Low-current analog comparators with adjustable reference
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-loaded UART bootloader
- Temperature range -40 to 85 ºC or -40 to 125 ºC
- Single power supply 2.2 to 3.6 V
- QSOP24, SOIC16, and QFN20 packages

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8BB1 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing non-volatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Each device is specified for 2.2 to 3.6 V operation, is AEC-Q100 qualified, and is available in 20-pin QFN, 16-pin SOIC or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

2. Ordering Information

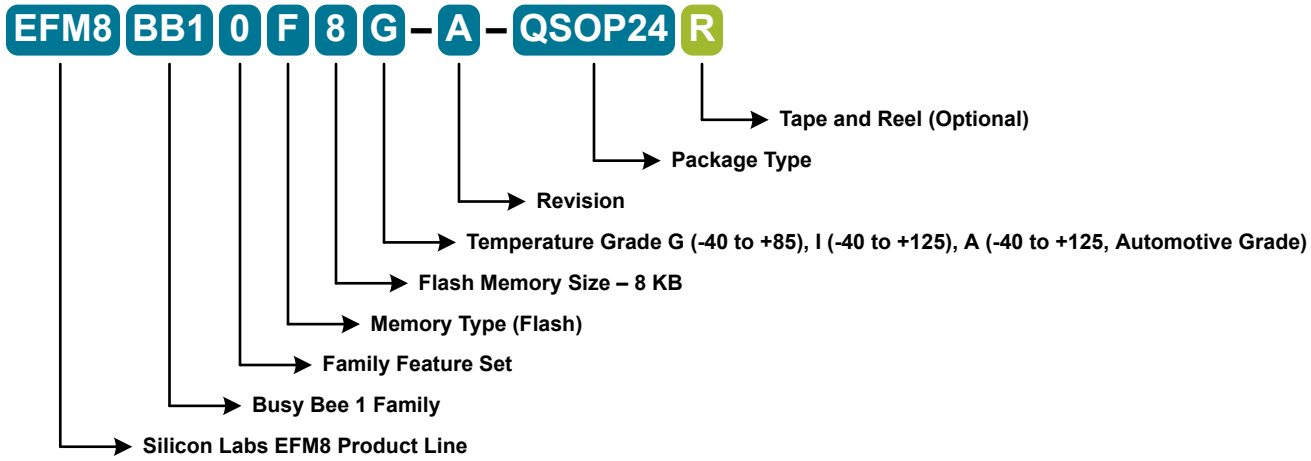


Figure 2.1. EFM8BB1 Part Numbering

All EFM8BB1 family members have the following features:

- CIP-51 Core running up to 25 MHz
- Two Internal Oscillators (24.5 MHz and 80 kHz)
- SMBus / I2C
- SPI
- UART
- 3-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 4 16-bit Timers
- 2 Analog Comparators
- 12-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- 16-bit CRC Unit
- AEC-Q100 qualified
- Pre-loaded UART bootloader

In addition to these features, each part number in the EFM8BB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8BB10F8G-A-QSOP24	8	512	18	16	8	8	Yes	-40 to +85 C	QSOP24
EFM8BB10F8G-A-QFN20	8	512	16	15	8	7	Yes	-40 to +85 C	QFN20
EFM8BB10F8G-A-SOIC16	8	512	13	12	6	6	Yes	-40 to +85 C	SOIC16
EFM8BB10F4G-A-QFN20	4	512	16	15	8	7	Yes	-40 to +85 C	QFN20
EFM8BB10F2G-A-QFN20	2	256	16	15	8	7	Yes	-40 to +85 C	QFN20
EFM8BB10F8I-A-QSOP24	8	512	18	16	8	8	Yes	-40 to +125 C	QSOP24

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8BB10F8I-A-QFN20	8	512	16	15	8	7	Yes	-40 to +125 C	QFN20
EFM8BB10F8I-A-SOIC16	8	512	13	12	6	6	Yes	-40 to +125 C	SOIC16
EFM8BB10F4I-A-QFN20	4	512	16	15	8	7	Yes	-40 to +125 C	QFN20
EFM8BB10F2I-A-QFN20	2	256	16	15	8	7	Yes	-40 to +125 C	QFN20
EFM8BB10F8A-A-QFN20	8	512	16	15	8	7	Yes	-40 to +125 C	QFN20
EFM8BB10F4A-A-QFN20	4	512	16	15	8	7	Yes	-40 to +125 C	QFN20
EFM8BB10F2A-A-QFN20	2	256	16	15	8	7	Yes	-40 to +125 C	QFN20

The A-grade (i.e. EFM8BB10F8A-A-QFN20) devices receive full automotive quality production status, including AEC-Q100 qualification, registration with International Material Data System (IMDS), and Part Production Approval Process (PPAP) documentation. PPAP documentation is available at www.silabs.com with a registered and NDA approved user account.

3.10 Bootloader

All devices come pre-programmed with a UART bootloader. This bootloader resides in the code security page, which is the last last page of code flash; it can be erased if it is not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

More information about the bootloader protocol and usage can be found in *AN945: EFM8 Factory Bootloader User Guide*. Application notes can be found on the Silicon Labs website (www.silabs.com/8bit-appnotes) or within Simplicity Studio by using the [**Application Notes**] tile.

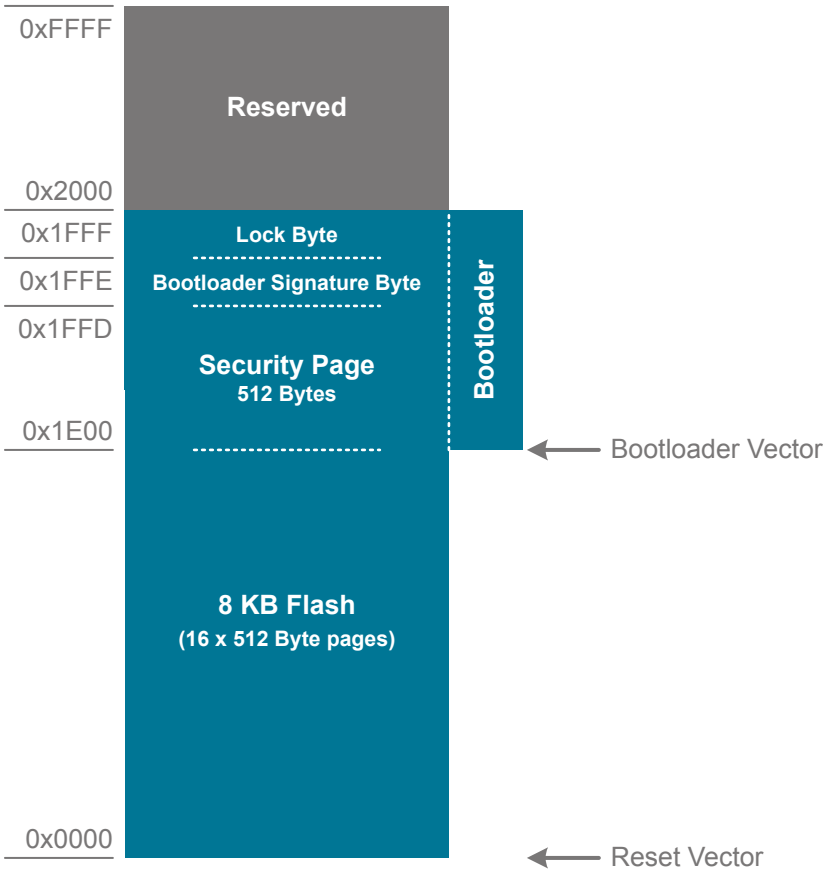


Figure 3.2. Flash Memory Map with Bootloader—8 KB Devices

Table 3.2. Summary of Pins for Bootloader Communication

Bootloader	Pins for Bootload Communication
UART	TX – P0.4
	RX – P0.5

Table 3.3. Summary of Pins for Bootload Mode Entry

Device Package	Pin for Bootload Mode Entry
QSOP24	P2.0 / C2D
QFN20	P2.0 / C2D
SOIC16	P2.0 / C2D

4.1.2 Power Consumption

Table 4.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current (G-grade devices, -40 °C to +85 °C)						
Normal Mode—Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	4.45	4.85	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	915	1150	µA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	250	290	µA
		F_{SYSCLK} = 80 kHz[3]	—	250	380	µA
Idle Mode—Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	2.05	2.3	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	550	700	µA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	125	130	µA
		F_{SYSCLK} = 80 kHz[3]	—	125	200	µA
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}	T_A = 25 °C	—	105	120	µA
		T_A = -40 to +85 °C	—	105	170	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	—	µA
Digital Core Supply Current (I-grade or A-grade devices, -40 °C to +125 °C)						
Normal Mode—Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	4.45	5.25	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	915	1600	µA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	250	290	µA
		F_{SYSCLK} = 80 kHz[3]	—	250	725	µA
Idle Mode—Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	2.05	2.6	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	550	1000	µA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	125	130	µA
		F_{SYSCLK} = 80 kHz[3]	—	125	550	µA
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}	T_A = 25 °C	—	105	120	µA
		T_A = -40 to +125 °C	—	105	270	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	—	µA
Analog Peripheral Supply Currents (-40 °C to +125 °C)						
High-Frequency Oscillator	I_{HFOSC}	Operating at 24.5 MHz, T_A = 25 °C	—	155	—	µA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	3.5	—	µA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit

Note:

1. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
2. Includes supply current from internal regulator, supply monitor, and High Frequency Oscillator.
3. Includes supply current from internal regulator, supply monitor, and Low Frequency Oscillator.
4. ADC0 always-on power excludes internal reference supply current.
5. The internal reference is enabled as-needed when operating the ADC in burst mode to save power.

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
V_{DD} Supply Monitor Threshold	V_{VDDM}		1.85[1]	1.95	2.1	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on V_{DD}	—	1.4	—	V
		Falling Voltage on V_{DD}	0.75	—	1.36	V
V_{DD} Ramp Time	t_{RMP}	Time to $V_{DD} \geq 2.2$ V	10	—	—	µs
Reset Delay from POR	t_{POR}	Relative to $V_{DD} \geq V_{POR}$	3	10	31	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	39	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	$F_{SYSCLK} > 1$ MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7.5	13.5	kHz
V_{DD} Supply Monitor Turn-On Time	t_{MON}		—	2	—	µs

Note:

1. MCU core, digital logic, flash memory, and RAM operation is guaranteed down to the minimum VDD Supply Monitor Threshold.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Slope Error	E_M	12 Bit Mode	—	±0.02	±0.1	%
		10 Bit Mode	—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Signal-to-Noise Plus Distortion	SNDR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	12 Bit Mode	—	71	—	dB
		10 Bit Mode	—	70	—	dB
Spurious-Free Dynamic Range	SFDR	12 Bit Mode	—	–79	—	dB
		10 Bit Mode	—	–74	—	dB

Note:
1. Absolute input pin voltage is limited by the V_{DD} supply.

4.1.8 Voltage Reference

Table 4.8. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}	1.65 V Setting	1.62	1.65	1.68	V
		2.4 V Setting, $V_{DD} \geq 2.6$ V	2.35	2.4	2.45	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	Sample Rate = 800 ksps; VREF = 3.0 V	—	5	—	µA

4.1.11 Comparators

Table 4.11. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	100	—	ns
		–100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential	—	1.5	—	µs
		–100 mV Differential	—	3.5	—	µs
Positive Hysterisis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysterisis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	–8	—	mV
		CPHYN = 10	—	–16	—	mV
		CPHYN = 11	—	–32	—	mV
Positive Hysterisis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysterisis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	–6	—	mV
		CPHYN = 10	—	–12	—	mV
		CPHYN = 11	—	–24	—	mV
Positive Hysterisis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysterisis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	–4.5	—	mV
		CPHYN = 10	—	–9	—	mV
		CPHYN = 11	—	–18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

4.2 Thermal Conditions

Table 4.15. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance (Junction to Ambient)	θ_{JA}	SOIC-16 Packages	—	70	—	°C/W
		QFN-20 Packages	—	60	—	°C/W
		QSOP-24 Packages	—	65	—	°C/W
Thermal Resistance (Junction to Case)	θ_{JC}	QFN-20 Packages	—	28.86	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 26 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		–55	125	°C
Storage Temperature	T_{STG}		–65	150	°C
Voltage on VDD	V_{DD}		GND–0.3	4.2	V
Voltage on I/O pins or RST	V_{IN}	V_{DD} ≥ 3.3 V	GND–0.3	5.8	V
		V < 3.3 V	GND–0.3	V_{DD}+2.5	V
Total Current Sunk into Supply Pin	I_{VDD}		—	200	mA
Total Current Sourced out of Ground Pin	I_{GND}		200	—	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	T_A = -40 °C to 85 °C	–40	105	°C
		T_A = -40 °C to 125 °C (I-grade or A-grade parts only)	-40	130	°C
Exposure to maximum rating conditions for extended periods may affect device reliability.					

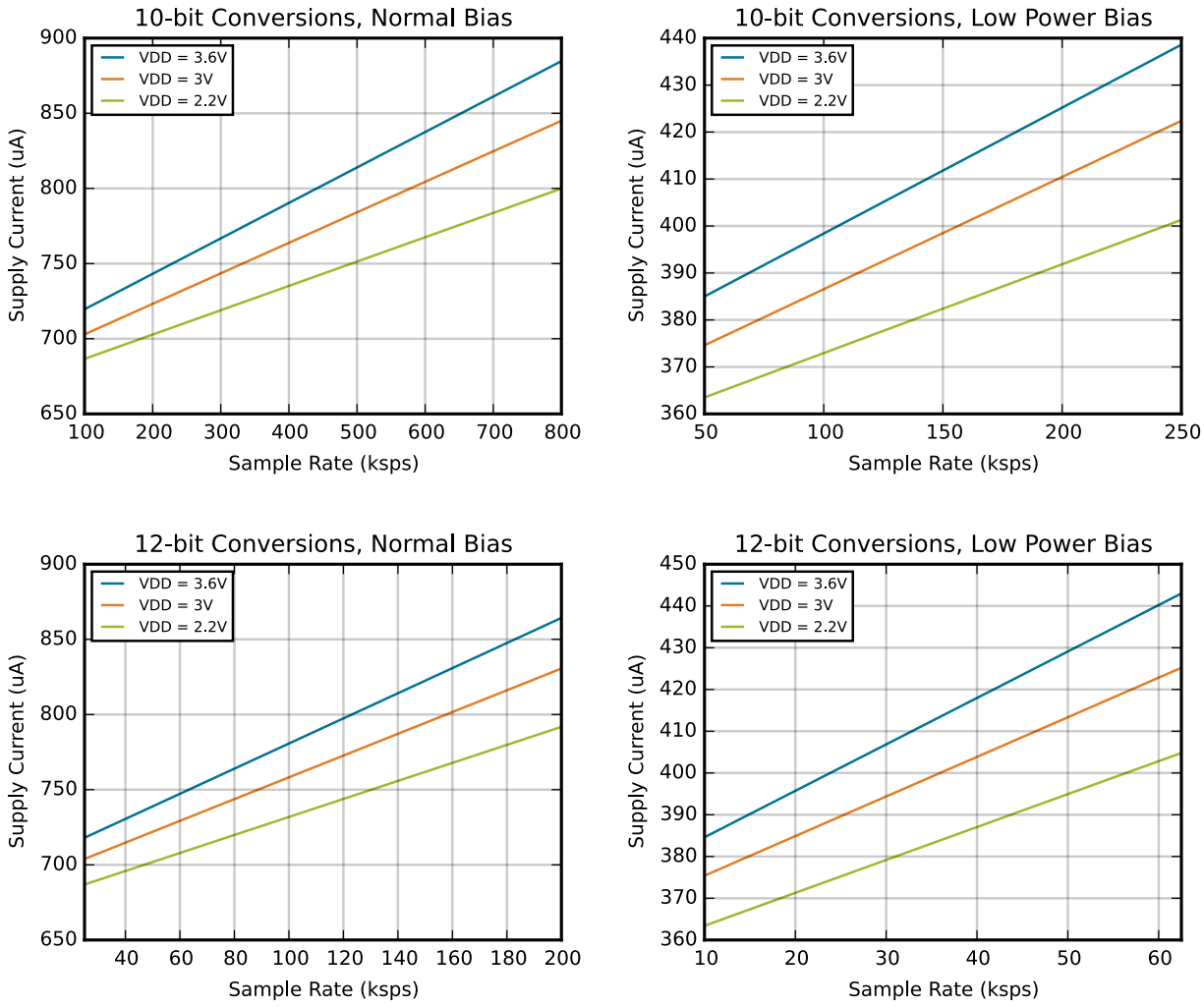


Figure 4.5. Typical ADC0 Supply Current in Normal (always-on) Mode

5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application note, "AN203: 8-bit MCU Printed Circuit Board Design Notes", contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND
4	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF
5	GND	Ground			
6	VDD	Supply Power Input			
7	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
8	P2.0 / C2D	Multifunction I/O / C2 Debug Data			
9	P1.7	Multifunction I/O	Yes	P1MAT.7	ADC0.15 CMP1P.7 CMP1N.7
10	P1.6	Multifunction I/O	Yes	P1MAT.6	ADC0.14 CMP1P.6 CMP1N.6
11	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13 CMP1P.5 CMP1N.5
12	P2.1	Multifunction I/O			
13	N/C	No Connection			
14	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP1P.4 CMP1N.4
15	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CMP1P.3 CMP1N.3
16	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CMP1P.2 CMP1N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	GND	Ground			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P2.0 / C2D	Multifunction I/O / C2 Debug Data			
7	P1.6	Multifunction I/O	Yes	P1MAT.6	ADC0.14 CMP1P.6 CMP1N.6
8	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13 CMP1P.5 CMP1N.5
9	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP1P.4 CMP1N.4
10	P1.3	Multifunction I/O	Yes	P1MAT.3	ADC0.11 CMP1P.3 CMP1N.3
11	P1.2	Multifunction I/O	Yes	P1MAT.2	ADC0.10 CMP1P.2 CMP1N.2
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9 CMP1P.1 CMP1N.1
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.0 CMP1N.0
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP0P.7 CMP0N.7
16	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.6 CMP0N.6

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
17	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0P.5 CMP0N.5
18	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.4 CMP0N.4
19	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 CMP0P.3 CMP0N.3
20	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.2 CMP0N.2
Center	GND	Ground			

8. QFN20 Package Specifications

8.1 QFN20 Package Dimensions

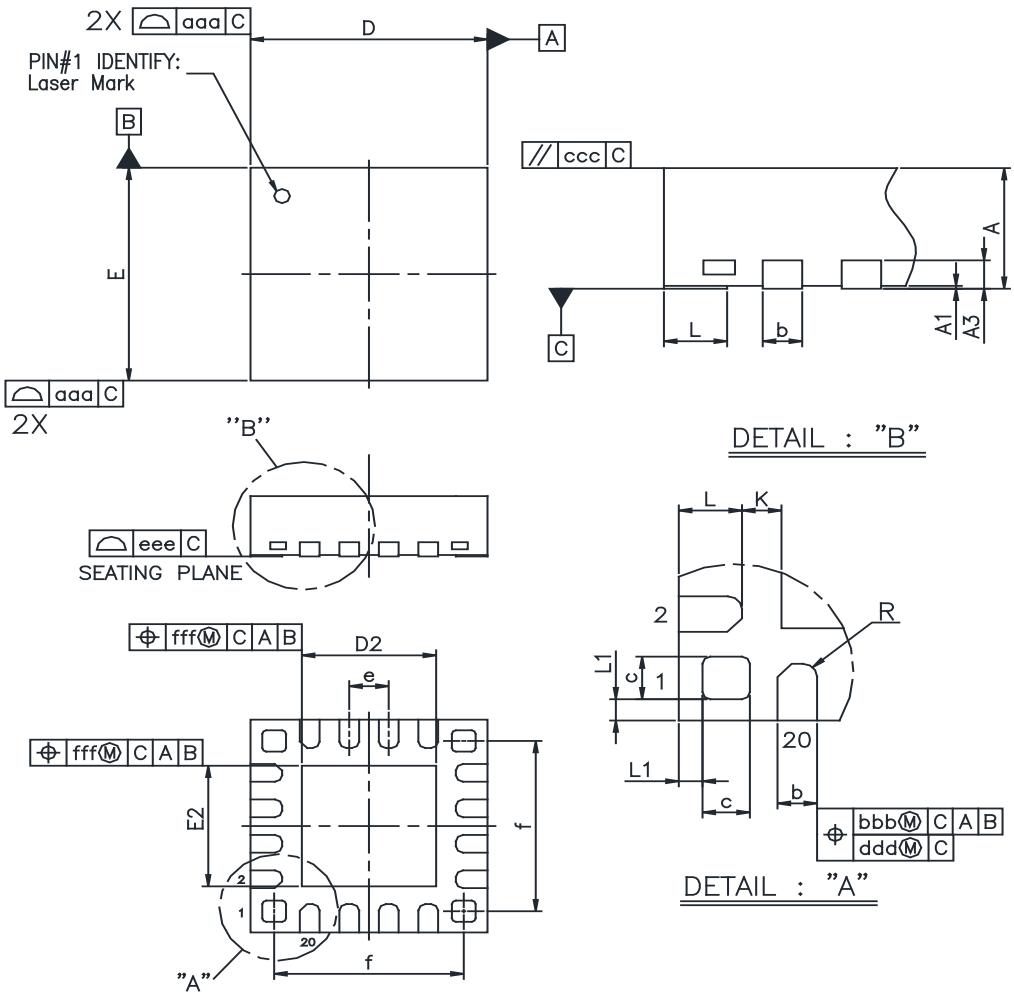


Figure 8.1. QFN20 Package Drawing

Table 8.1. QFN20 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A3		0.20 REF	
b	0.18	0.25	0.30
c	0.25	0.30	0.35
D		3.00 BSC	
D2	1.6	1.70	1.80
e		0.50 BSC	

Dimension	Min	Typ	Max
E		3.00 BSC	
E2	1.60	1.70	1.80
f		2.50 BSC	
L	0.30	0.40	0.50
K		0.25 REF	
R	0.09	0.125	0.15
aaa		0.15	
bbb		0.10	
ccc		0.10	
ddd		0.05	
eee		0.08	
fff		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. The drawing complies with JEDEC MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10. Revision History

10.1 Revision 1.5

October 7th, 2016

Added A-grade parts.

Added specifications for 4.1.13 SMBus.

Added bootloader pinout information to 3.10 Bootloader.

Added CRC Calculation Time to 4.1.4 Flash Memory.

Added Thermal Resistance (Junction to Case) for QFN20 packages to 4.2 Thermal Conditions.

Added a note linking to the Typical VOH and VOL Performance graphs in 4.1.12 Port I/O.

Added 4.1.10 1.8 V Internal LDO Voltage Regulator.

Added a note to 3.1 Introduction referencing the Reference Manual.

10.2 Revision 1.4

April 22nd, 2016

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in 3.10 Bootloader.

Added I-grade devices.

Added a note that all GPIO values are undefined when VDD is below 1 V to 4.1.1 Recommended Operating Conditions.

Adjusted the Total Current Sunk into Supply Pin and Total Current Sourced out of Ground Pin specifications in 4.3 Absolute Maximum Ratings.

10.3 Revision 1.3

January 7th, 2016

Added 5.2 Debug.

Updated 3.10 Bootloader to include information about the bootloader implementation.

10.4 Revision 1.2

Updated Port I/O specifications in 4.1.12 Port I/O to include new V_{OL} specifications.

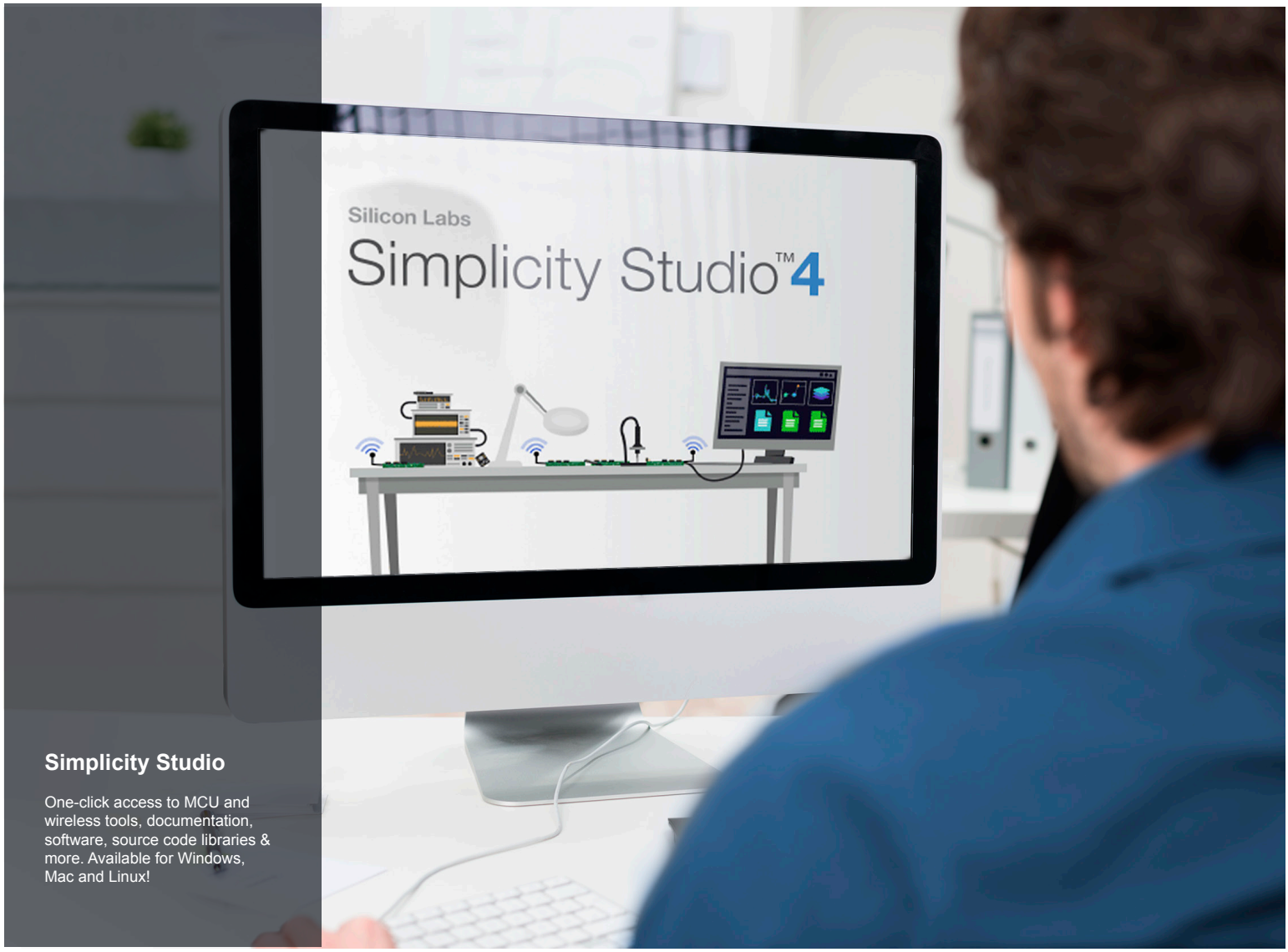
Added a note to Table 4.3 Reset and Supply Monitor on page 15 regarding guaranteed operation.

Updated package diagram and landing diagram specifications for the QFN20 package.

10.5 Revision 1.1

Initial release.

Table of Contents



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